


<b>Search Notes</b>  	<b>Application/Control No.</b>  10705591	<b>Applicant(s)/Patent Under Reexamination</b>  LEE ET AL.
	<b>Examiner</b>  Han, Jason M	<b>Art Unit</b>  2875

SEARCHED			
Class	Subclass	Date	Examiner
362	600, 606, 623-629	05/25/2006	JMH
349	56, 61-62, 65, 70	05/25/1962	JMH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST - (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	05/25/2006	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	11/13/2006	JMH
Search Update - EAST (US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB) - See Printout	4/27/2007	JMH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	EAST (US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB) - See Printout	4/27/2007	JMH